

Recent Test Results on PALs: Cypress BiCMOS 22V10C devices

Test mode: Dynamic, 1 MHz, shift register of alternating 1's and 0's

Protons at UCD (6/97)

Mfr: Elmo (Cypress die)

Part #: JT22V10-10 ETUFP (Jackson and Tull part number)

Results: Upsets in flip-flops with 63 MeV protons.

Cross-section is 2E-11 per flip-flop

No upsets in combinational logic gates

Heavy ion tests at BNL (7/97)

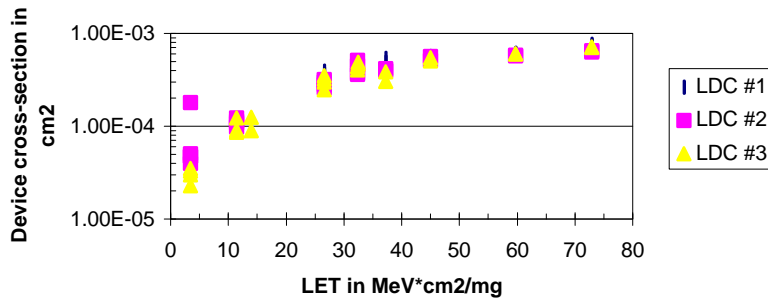
Results for 3 LDCs are graphed below.

LDC #1 002611202

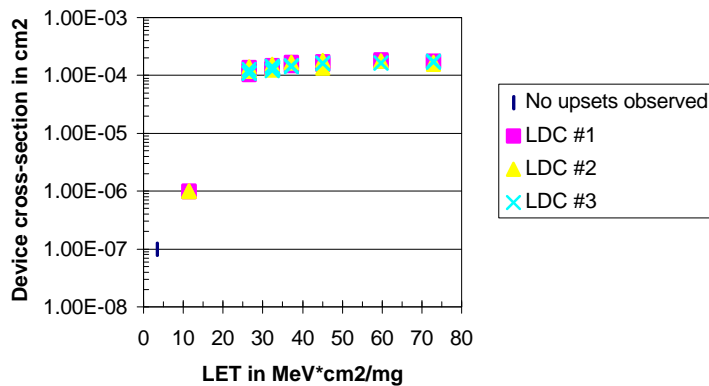
LDC #2 XC34950484

LDC #3 XC349608493

22V10C PALs - flip-flop cross-section (divide by 8 to get per flip-flop)



22V10C PALs - combinational logic cross-sections per device



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